


TEST REPORT

 CTK Co., Ltd. <small>The Power Leader of Global Regulatory Certification</small>	CTK Co., Ltd. (Ho-dong) 113, Yejik-ro, Cheoin-gu, Yongin-shi Gyeonggi-do KOREA, REPUBLIC OF Tel: +82-31-339-9970 Fax: +82-31-624-9501	REPORT No.: CTK-2020-04917 Page (1) / (12) pages	
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1. Applicant

- Name : Hanwha Techwin Co., Ltd.
- Address : Hanwha Techwin R&D center, 6 Pangyo-ro 319Beon-gil,
Bundang-gu, Seongnam-si, Gyeonggi-do, 13488 KOREA
- Date of Receipt..... : 2017-11-01

2. Manufacturer

- Name : Hanwha Techwin Co., Ltd.

3. Use of Report : Quality control

4. Test sample / Model : NETWORK CAMERA / XNP-6370RH* (*N:NT/P:PAL)

5. Date(s) of test : 2017-11-07

6. Test Standard (Method) used..... : Requested Test Specification of Applicant

7. Testing Environment..... : Temperature: (25.0 ± 10.0) °C, Humidity: (50 ± 25) %R.H., Air Pressure: (99.0 ± 2) kPa

8. Results : Refer to each test items

The results shown in this test report refer only to the sample(s) tested unless otherwise stated.
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Approval	Tested by:	Technical Manager:
	Min-Gi Mun	YenHwang Jung

(Signature)

(Signature)

2020-12-16

CTK Co., Ltd.

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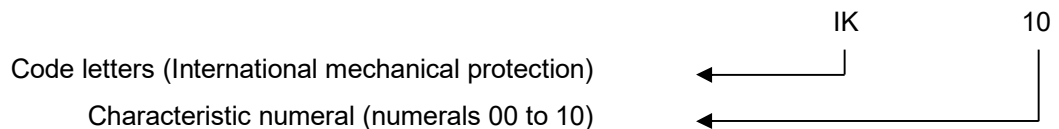
Test place

Institution name	CTK Co., Ltd.
Address	113, Yejik-ro, Cheoin-gu, Yongin-si, Gyeonggi-do, Republic of Korea

1. Degrees of protection provided by enclosures for electrical equipment against external mechanical impacts (IK code)

1.1 Test standard: KS C IEC 62262: 2005

1.2 Arrangement of the IK code



1.3 Vertical Hammer

1.3.1 Test equipment

Equipment	Model	Manufacturer	Serial
Vertical Hammer	20J	Kingpo	TX028-1


1.3.2 Test condition

IK code	Impact Energy (J)	Equivalent mass (kg)	Drop height (mm ± 1%)	Application
00	Non-protected	-	-	<input type="checkbox"/>
01	0.14	0.25	56	<input type="checkbox"/>
02	0.20	0.25	80	<input type="checkbox"/>
03	0.35	0.25	140	<input type="checkbox"/>
04	0.50	0.25	200	<input type="checkbox"/>
05	0.70	0.25	280	<input type="checkbox"/>
06	1.00	0.25	400	<input type="checkbox"/>
07	2.00	0.50	400	<input type="checkbox"/>
08	5.00	1.70	300	<input type="checkbox"/>
09	10.00	5.00	200	<input type="checkbox"/>
10	20.00	5.00	400	<input checked="" type="checkbox"/>

- Impact times: five times for each of the exposed surface. (Do not impact more than 3 times in the same spot)

1.3.3 Check Item

- Check the separation of the component.
- Check the visual damage of the product outside.

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1.3.5 Test Result

Characteristic numeral	Remark
IK 10	The enclosure is Scratch (Reference to Page 6 ~ 7)

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Manufacturer's name

Name and address of factory (ies)	1) D-TECH CO.,LTD. 173-25, Saneop-ro, Gwonseon-gu, Suwon-si, Gyeonggi-do, Korea (Suwon Industrial Complex) 2) HANWHA TECHWIN SECURITY VIETNAM CO.,LTD Lot O-2, Que Vo Industrial Zone extended area, Nam Son commune, Bac Ninh city, Bac Ninh province, Vietnam
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Model description

Basic Model	XNP-6370RH
Series model	PNP-9200RH, XNP-6320RH, XNP-6330RH, QNP-6230RH, HCP-6370RH, XNP-8330RH, HCP-6320RH, XNP-6371RH, XNP-6550RH, XNP-6450RH, XNP-6420RH, HCP-6550RH, HCP-6450RH, HCP-6420RH
Model differences	Use of the same external shape and materials (case, finishing material, PCB, cable, etc.), differences in electronic parts inside the product.

2. Attachment

2.1 Products



2.2 Test photos

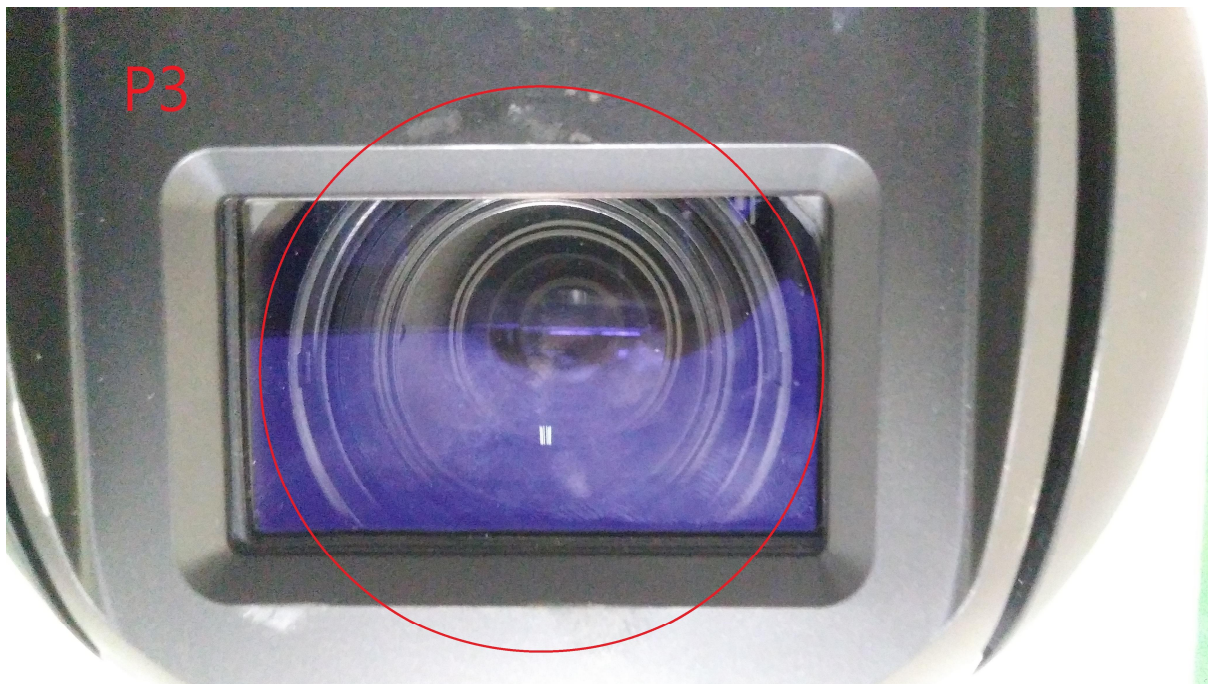


2.3 Photos after test

[P1, P2]



[P3]



[P4]



[P5]



2.4 Enclosure Dimensions or Impact point (Unit: mm)

